

18th International School on the Effects of Radiation on Embedded Systems
for Space Applications (SERESSA)

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Organizers:



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Single Event Multiple Transient Analysis of Digital Circuits using Satisfiability Modulo Theories

Thursday, 8 December 2022 14:20 (50 minutes)

In this talk, we will be discussing the practical use of formal based techniques, such as SAT, SMT and probabilistic model checker to analyze SEEs at logical and higher abstraction levels. Through examples, we will illustrate each approach and its benefits.

Presenter: AIT MOHAMED, Otmane (Concordia University)